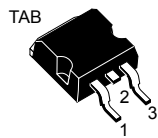
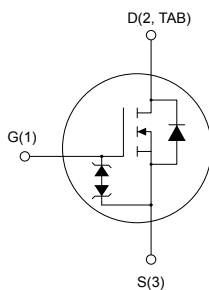


# N-channel 800 V, 400 mΩ typ., 12 A MDmesh K5 Power MOSFET in a D<sup>2</sup>PAK package


**D<sup>2</sup>PAK**


AM01476v1\_tab


**Product status link**
[STB14N80K5](#)
**Product summary**

|                   |                    |
|-------------------|--------------------|
| <b>Order code</b> | STB14N80K5         |
| <b>Marking</b>    | 14N80K5            |
| <b>Package</b>    | D <sup>2</sup> PAK |
| <b>Packing</b>    | Tape and reel      |

## Features

| Order code | V <sub>DS</sub> | R <sub>DS(on)</sub> max. | I <sub>D</sub> |
|------------|-----------------|--------------------------|----------------|
| STB14N80K5 | 800 V           | 445 mΩ                   | 12 A           |

- Industry's lowest R<sub>DS(on)</sub> x area
- Ultra-low gate charge
- Very low FoM (figure of merit)
- Zener-protected
- 100% avalanche tested

## Applications

- Switching applications

## Description

This very high voltage N-channel Power MOSFET is designed using MDmesh K5 technology based on an innovative proprietary vertical structure. The result is a dramatic reduction in on-resistance and ultra-low gate charge for applications requiring superior power density and high efficiency.

# 1 Electrical ratings

**Table 1. Absolute maximum ratings**

| Symbol         | Parameter                                                         | Value      | Unit               |
|----------------|-------------------------------------------------------------------|------------|--------------------|
| $V_{GS}$       | Gate-source voltage                                               | $\pm 30$   | V                  |
| $I_D$          | Drain current (continuous) at $T_C = 25\text{ }^{\circ}\text{C}$  | 12         | A                  |
|                | Drain current (continuous) at $T_C = 100\text{ }^{\circ}\text{C}$ | 7.4        |                    |
| $I_{DM}^{(1)}$ | Drain current (pulsed)                                            | 48         | A                  |
| $P_{TOT}$      | Total power dissipation at $T_C = 25\text{ }^{\circ}\text{C}$     | 130        | W                  |
| $dv/dt^{(2)}$  | Peak diode recovery voltage slope                                 | 4.5        | V/ns               |
| $dv/dt^{(3)}$  | MOSFET $dv/dt$ ruggedness                                         | 50         | V/ns               |
| $T_{stg}$      | Storage temperature range                                         | -55 to 150 | $^{\circ}\text{C}$ |
| $T_J$          | Operating junction temperature range                              |            | $^{\circ}\text{C}$ |

- Pulse width is limited by safe operating area.
- $V_{DD} = 640\text{ V}$ ,  $I_{SD} \leq 12\text{ A}$ ,  $di/dt = 100\text{ A}/\mu\text{s}$ ,  $V_{DS}(\text{peak}) < V_{(BR)DSS}$ .
- $V_{DD} \leq 640\text{ V}$ .

**Table 2. Thermal data**

| Symbol           | Parameter                               | Value | Unit                        |
|------------------|-----------------------------------------|-------|-----------------------------|
| $R_{thJC}$       | Thermal resistance, junction-to-case    | 0.96  | $^{\circ}\text{C}/\text{W}$ |
| $R_{thJA}^{(1)}$ | Thermal resistance, junction-to-ambient | 30    | $^{\circ}\text{C}/\text{W}$ |

- When mounted on a standard 1 inch<sup>2</sup> area of FR-4 PCB with 2-oz copper.

**Table 3. Avalanche characteristics**

| Symbol   | Parameter                                                                                                              | Value | Unit |
|----------|------------------------------------------------------------------------------------------------------------------------|-------|------|
| $I_{AR}$ | Avalanche current, repetitive or non-repetitive (pulse width limited by $T_J$ max.)                                    | 4     | A    |
| $E_{AS}$ | Single pulse avalanche energy (starting $T_J = 25\text{ }^{\circ}\text{C}$ , $I_D = I_{AR}$ , $V_{DD} = 50\text{ V}$ ) | 270   | mJ   |

## 2 Electrical characteristics

$T_C = 25\text{ }^{\circ}\text{C}$  unless otherwise specified.

**Table 4. Static**

| Symbol        | Parameter                         | Test conditions                                                                             | Min. | Typ. | Max.     | Unit          |
|---------------|-----------------------------------|---------------------------------------------------------------------------------------------|------|------|----------|---------------|
| $V_{(BR)DSS}$ | Drain-source breakdown voltage    | $V_{GS} = 0\text{ V}$ , $I_D = 1\text{ mA}$                                                 | 800  | -    | -        | V             |
| $I_{DSS}$     | Zero gate voltage drain current   | $V_{GS} = 0\text{ V}$ , $V_{DS} = 800\text{ V}$                                             | -    | -    | 1        | $\mu\text{A}$ |
|               |                                   | $V_{GS} = 0\text{ V}$ , $V_{DS} = 800\text{ V}$ , $T_C = 125\text{ }^{\circ}\text{C}^{(1)}$ | -    | -    | 50       |               |
| $I_{GSS}$     | Gate-body leakage current         | $V_{DS} = 0\text{ V}$ , $V_{GS} = \pm 20\text{ V}$                                          | -    | -    | $\pm 10$ | $\mu\text{A}$ |
| $V_{GS(th)}$  | Gate threshold voltage            | $V_{DS} = V_{GS}$ , $I_D = 100\text{ }\mu\text{A}$                                          | 3    | 4    | 5        | V             |
| $R_{DS(on)}$  | Static drain-source on-resistance | $V_{GS} = 10\text{ V}$ , $I_D = 6\text{ A}$                                                 | -    | 400  | 445      | m $\Omega$    |

1. Specified by design, not tested in production.

**Table 5. Dynamic**

| Symbol            | Parameter                                    | Test conditions                                                                                                                                  | Min. | Typ. | Max. | Unit     |
|-------------------|----------------------------------------------|--------------------------------------------------------------------------------------------------------------------------------------------------|------|------|------|----------|
| $C_{iss}$         | Input capacitance                            | $V_{DS} = 100\text{ V}$ , $f = 1\text{ MHz}$ , $V_{GS} = 0\text{ V}$                                                                             | -    | 620  | -    | pF       |
| $C_{oss}$         | Output capacitance                           |                                                                                                                                                  | -    | 60   | -    | pF       |
| $C_{rss}$         | Reverse transfer capacitance                 |                                                                                                                                                  | -    | 0.8  | -    | pF       |
| $C_{o(tr)}^{(1)}$ | Equivalent output capacitance time related   | $V_{DS} = 0\text{ to }640\text{ V}$ , $V_{GS} = 0\text{ V}$                                                                                      | -    | 107  | -    | pF       |
| $C_{o(er)}^{(2)}$ | Equivalent output capacitance energy related |                                                                                                                                                  | -    | 39   | -    | pF       |
| $R_g$             | Intrinsic gate resistance                    | $f = 1\text{ MHz}$ , $I_D = 0\text{ A}$                                                                                                          | -    | 6.5  | -    | $\Omega$ |
| $Q_g$             | Total gate charge                            | $V_{DD} = 640\text{ V}$ , $I_D = 12\text{ A}$ , $V_{GS} = 0\text{ to }10\text{ V}$<br>(see the Figure 15. Test circuit for gate charge behavior) | -    | 22   | -    | nC       |
| $Q_{gs}$          | Gate-source charge                           |                                                                                                                                                  | -    | 4.3  | -    | nC       |
| $Q_{gd}$          | Gate-drain charge                            |                                                                                                                                                  | -    | 16.5 | -    | nC       |

1.  $C_{o(tr)}$  is a constant capacitance value that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 80%  $V_{DSS}$ .

2.  $C_{o(er)}$  is a constant capacitance value that gives the same stored energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 80%  $V_{DSS}$ .

**Table 6. Switching times**

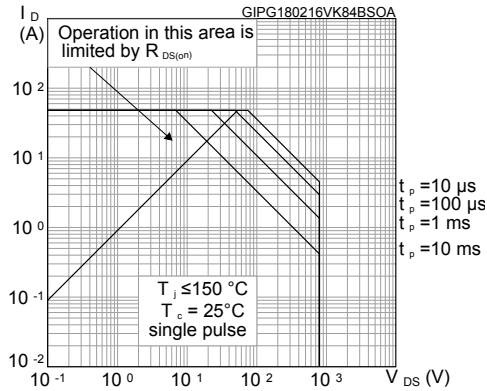
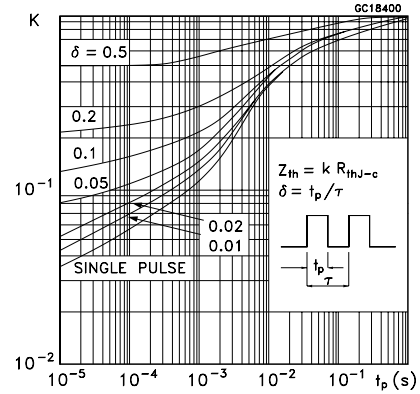
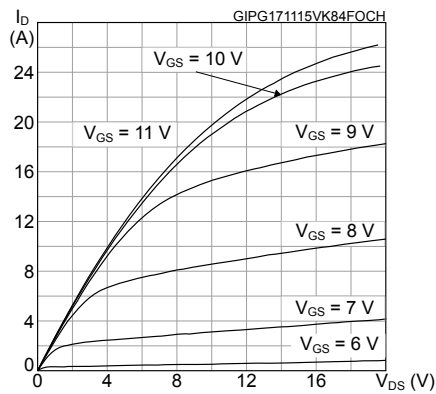
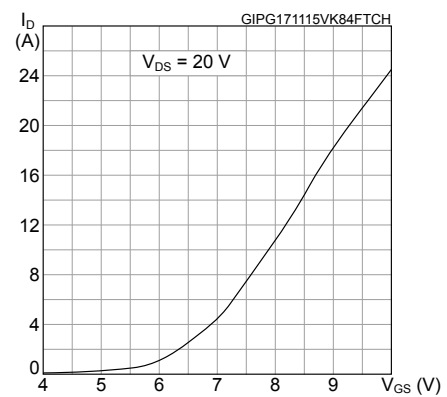
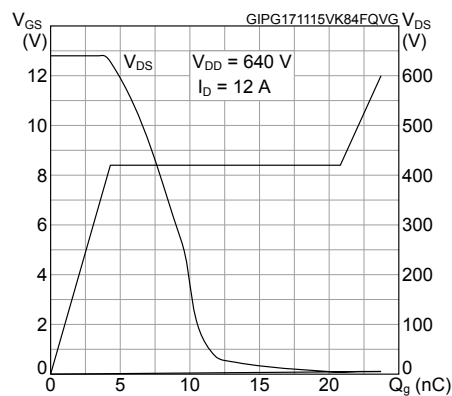
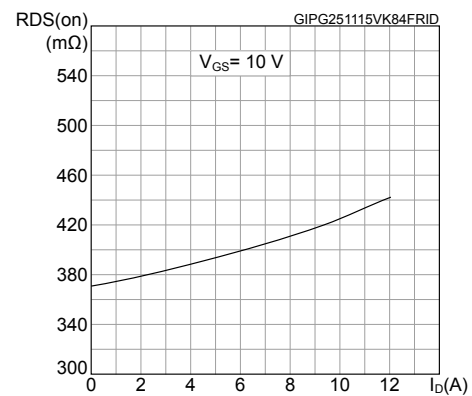
| Symbol       | Parameter           | Test conditions                                                                                             | Min. | Typ. | Max. | Unit |
|--------------|---------------------|-------------------------------------------------------------------------------------------------------------|------|------|------|------|
| $t_{d(on)}$  | Turn-on delay time  | $V_{DD} = 400\text{ V}$ , $I_D = 6\text{ A}$ ,<br>$R_G = 4.7\text{ }\Omega$ , $V_{GS} = 10\text{ V}$        | -    | 12.5 | -    | ns   |
| $t_r$        | Rise time           |                                                                                                             | -    | 8    | -    | ns   |
| $t_{d(off)}$ | Turn-off delay time | (see the Figure 14. Test circuit for resistive load switching times and Figure 19. Switching time waveform) | -    | 33   | -    | ns   |
| $t_f$        | Fall time           |                                                                                                             | -    | 10   | -    | ns   |

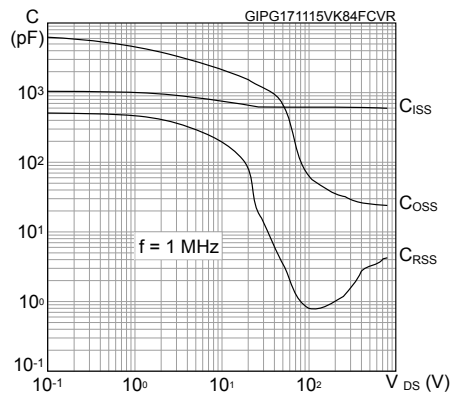
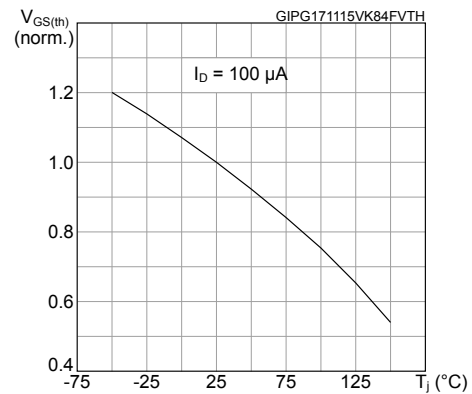
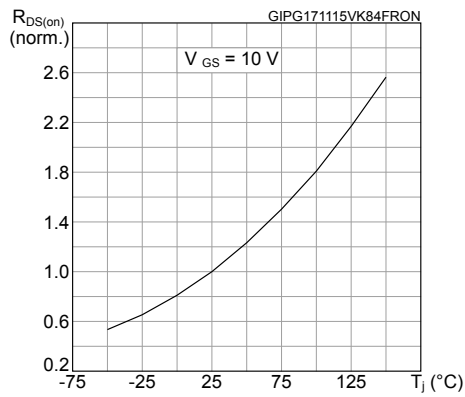
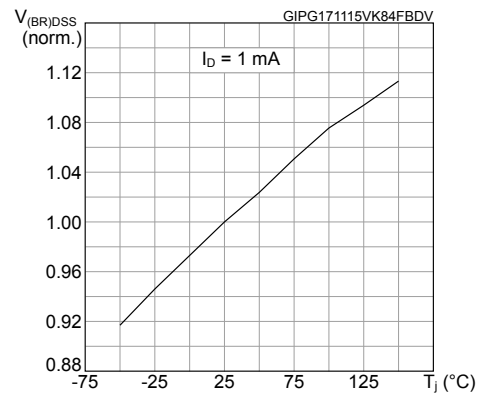
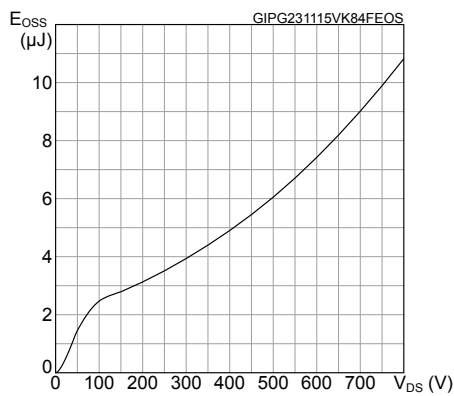
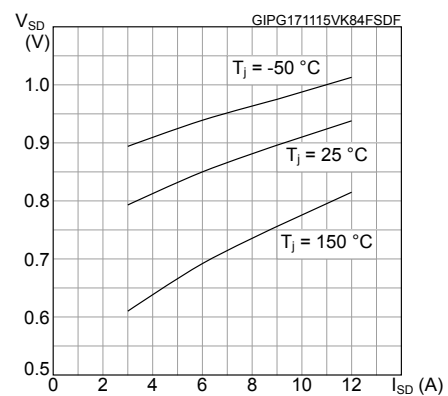
**Table 7. Source-drain diode**

| Symbol          | Parameter                     | Test conditions                                                                                                             | Min. | Typ. | Max. | Unit          |
|-----------------|-------------------------------|-----------------------------------------------------------------------------------------------------------------------------|------|------|------|---------------|
| $I_{SD}$        | Source-drain current          |                                                                                                                             | -    | -    | 12   | A             |
| $I_{SDM}^{(1)}$ | Source-drain current (pulsed) |                                                                                                                             | -    | -    | 48   | A             |
| $V_{SD}^{(2)}$  | Forward on voltage            | $V_{GS} = 0\text{ V}$ , $I_{SD} = 12\text{ A}$                                                                              | -    | -    | 1.5  | V             |
| $t_{rr}$        | Reverse recovery time         | $I_{SD} = 12\text{ A}$ , $di/dt = 100\text{ A}/\mu\text{s}$ ,<br>$V_{DD} = 60\text{ V}$                                     | -    | 365  | -    | ns            |
| $Q_{rr}$        | Reverse recovery charge       |                                                                                                                             | -    | 4.77 | -    | $\mu\text{C}$ |
| $I_{RRM}$       | Reverse recovery current      | (see the Figure 16. Test circuit for inductive load switching and diode recovery times)                                     | -    | 26   | -    | A             |
| $t_{rr}$        | Reverse recovery time         | $I_{SD} = 12\text{ A}$ , $di/dt = 100\text{ A}/\mu\text{s}$ ,<br>$V_{DD} = 60\text{ V}$ , $T_J = 150\text{ }^\circ\text{C}$ | -    | 485  | -    | ns            |
| $Q_{rr}$        | Reverse recovery charge       |                                                                                                                             | -    | 5.85 | -    | $\mu\text{C}$ |
| $I_{RRM}$       | Reverse recovery current      | (see the Figure 16. Test circuit for inductive load switching and diode recovery times)                                     | -    | 24   | -    | A             |

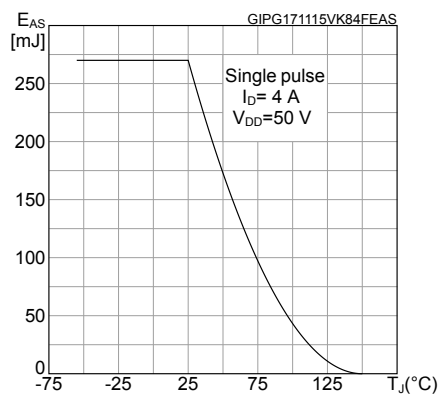
1. Pulse width is limited by safe operating area.
2. Pulse test: pulse duration = 300  $\mu\text{s}$ , duty cycle 1.5%.

## 2.1 Electrical characteristics (curves)

**Figure 1. Safe operating area**

**Figure 2. Normalized transient thermal impedance**

**Figure 3. Typical output characteristics**

**Figure 4. Typical transfer characteristics**

**Figure 5. Typical gate charge characteristics**

**Figure 6. Typical drain-source on-resistance**


**Figure 7. Typical capacitance characteristics**

**Figure 8. Normalized gate threshold vs temperature**

**Figure 9. Normalized on-resistance vs temperature**

**Figure 10. Normalized breakdown voltage vs temperature**

**Figure 11. Typical output capacitance stored energy**

**Figure 12. Typical reverse diode forward characteristics**


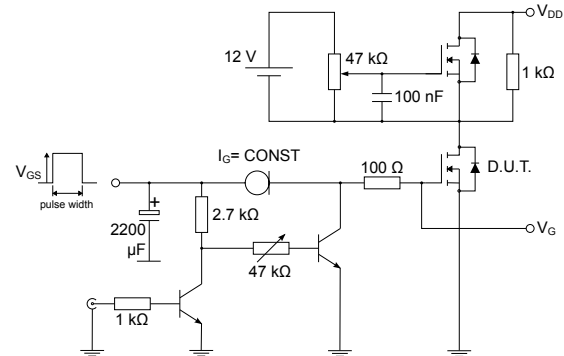
**Figure 13. Maximum avalanche energy vs temperature**



### 3 Test circuits

**Figure 14. Test circuit for resistive load switching times**


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**Figure 15. Test circuit for gate charge behavior**


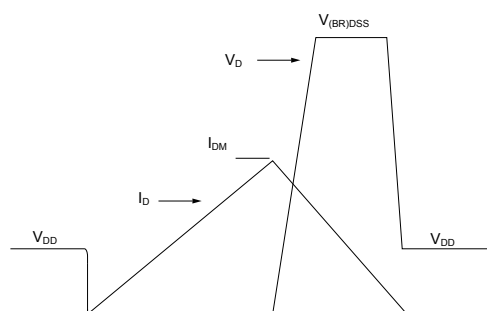
AM01469v1

**Figure 16. Test circuit for inductive load switching and diode recovery times**

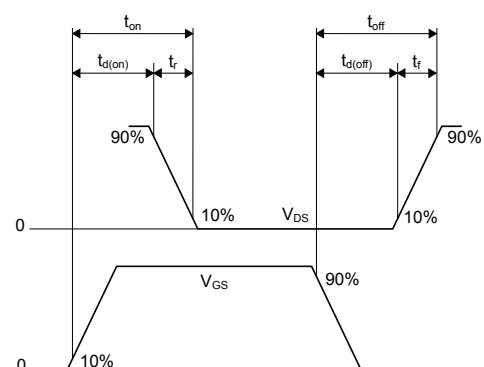

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**Figure 17. Unclamped inductive load test circuit**


AM01471v1

**Figure 18. Unclamped inductive waveform**


AM01472v1

**Figure 19. Switching time waveform**


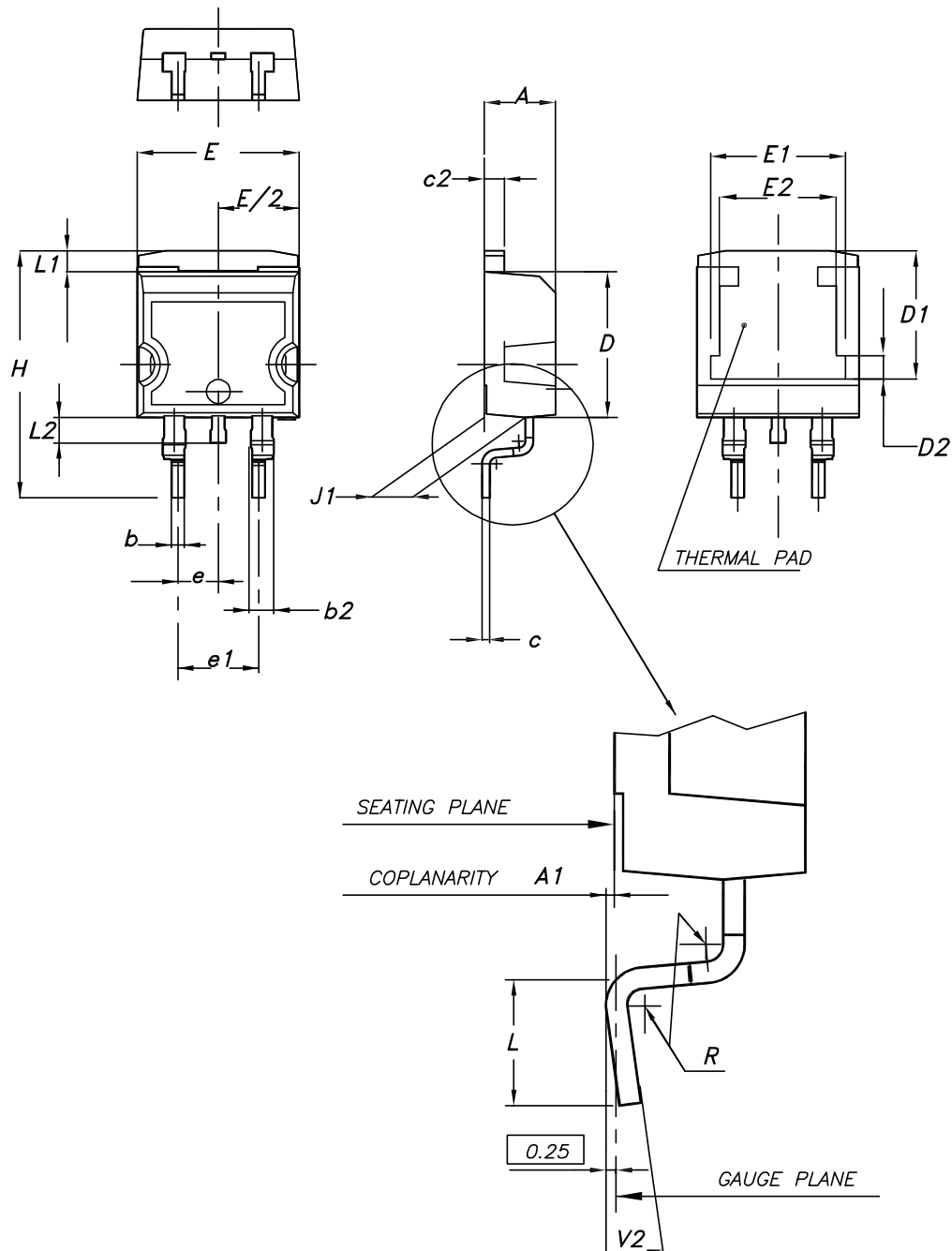
AM01473v1

## 4 Package information

To meet environmental requirements, ST offers these devices in different grades of **ECOPACK** packages, depending on their level of environmental compliance. ECOPACK specifications, grade definitions, and product status are available at: [www.st.com](http://www.st.com). ECOPACK is an ST trademark.

### 4.1 D<sup>2</sup>PAK (TO-263) type A package information

Figure 20. D<sup>2</sup>PAK (TO-263) type A package outline

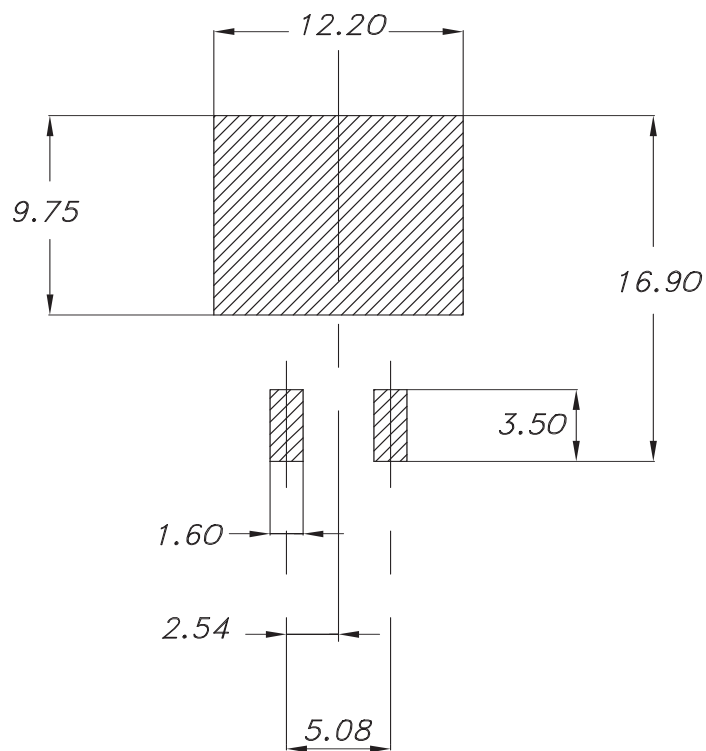


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**Table 8. D<sup>2</sup>PAK (TO-263) type A package mechanical data**

| Dim. | mm    |      |       |
|------|-------|------|-------|
|      | Min.  | Typ. | Max.  |
| A    | 4.40  |      | 4.60  |
| A1   | 0.03  |      | 0.23  |
| b    | 0.70  |      | 0.93  |
| b2   | 1.14  |      | 1.70  |
| c    | 0.45  |      | 0.60  |
| c2   | 1.23  |      | 1.36  |
| D    | 8.95  |      | 9.35  |
| D1   | 7.50  | 7.75 | 8.00  |
| D2   | 1.10  | 1.30 | 1.50  |
| E    | 10.00 |      | 10.40 |
| E1   | 8.30  | 8.50 | 8.70  |
| E2   | 6.85  | 7.05 | 7.25  |
| e    |       | 2.54 |       |
| e1   | 4.88  |      | 5.28  |
| H    | 15.00 |      | 15.85 |
| J1   | 2.49  |      | 2.69  |
| L    | 2.29  |      | 2.79  |
| L1   | 1.27  |      | 1.40  |
| L2   | 1.30  |      | 1.75  |
| R    |       | 0.40 |       |
| V2   | 0°    |      | 8°    |

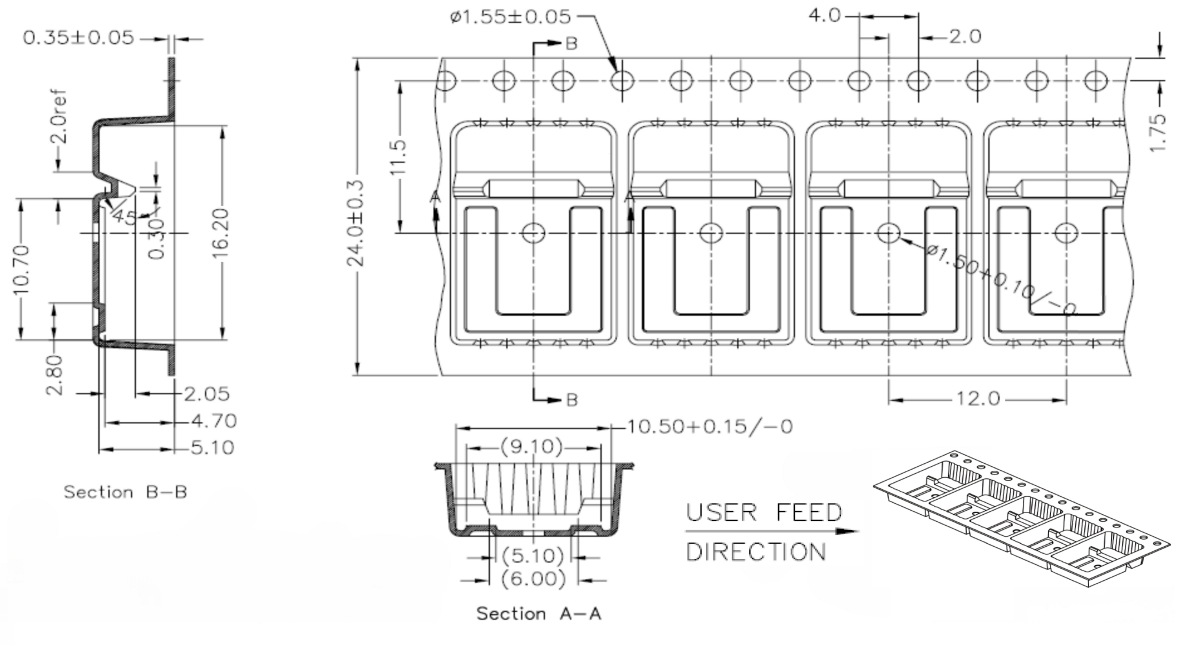
**Figure 21. D<sup>2</sup>PAK (TO-263) recommended footprint (dimensions are in mm)**



0079457\_Rev27\_footprint

## 4.2 D<sup>2</sup>PAK packing information

Figure 22. D<sup>2</sup>PAK tape drawing (dimensions are in mm)



DM01095771\_2

## Revision history

**Table 9. Document revision history**

| Date        | Version | Changes                                                                         |
|-------------|---------|---------------------------------------------------------------------------------|
| 18-Feb-2016 | 1       | First release.                                                                  |
| 28-Oct-2025 | 2       | Updated <a href="#">Section 4: Package information</a> .<br>Minor text changes. |

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